

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Tamai IE Karl	Art Unit 2834	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5064782	11-1991	Nishiguchi	437/216
	B	US-6116863	09-2000	Ahn et al.	417/322
	C	US-6262827	07-2001	Ueda et al.	359/224
	D	US-2002/0021055	02-2002	Lee et al.	310/309
	E	US-2002/0054415	05-2002	Lee	359/223
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000-147419 ✓	05-2000	Japan	Victor	G02B026/08
	O	2002-137200 ✓	05-2002	Japan	Lee	B81B003/00
	P	5-76,186 ✓	03-1993	Japan	Nakagawa	H02N001/00
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.